

Application/Control No.	Applicant(s)/Patent under Reexamination LO ET AL.	
10/749,565		
Examiner	Art Unit	
Patricia Leith	1655	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
updated EAST:JPO,EPO,DERWENT,USPATF ULL,USPGPUBS,OCRBACKFILE	4/12/2006	PL	
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